

09954809 CLS

Most Frequently Occurring Classifications of Patents Returned
From A Search of 09954809 on September 30, 2003

Original Classifications

7 324/765
5 324/601
3 327/108
3 365/230.05
3 714/736
2 702/85
2 714/726
2 714/727
2 714/740

Cross-Reference Classifications

4 324/638
3 324/158.1
3 324/601
3 324/763
3 714/724
2 324/637
2 326/30
2 326/90
2 327/563
2 327/68
2 356/364
2 365/200
2 365/201
2 365/230.05
2 713/500
2 714/727

PLW's
Report

Combined Classifications

8 324/601
7 324/765
5 324/638
5 365/230.05
4 324/158.1
4 714/724
4 714/727
4 714/736
3 324/637
3 324/763
3 327/108
3 365/201
3 702/85
2 324/627

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2 326/30
2 326/90
2 327/563
2 327/68
2 356/364
2 356/73.1
2 365/189.04
2 365/200
2 702/76
2 713/500
2 714/726
2 714/740

09954809_CLSTITLES

Titles of Most Frequently Occurring Classifications of Patents Returned

From A Search of 09954809 on September 30, 2003

8 324/601 (5 OR, 3 XR)
 Class 324 : ELECTRICITY: MEASURING AND TESTING
 324/600 IMPEDANCE, ADMITTANCE OR OTHER QUANTITIES
 REPRESENTATIVE OF ELECTRICAL STIMULUS/RESP

ONSE

324/601 RELATIONSHIPS
 .Calibration

7 324/765 (7 OR, 0 XR)
 Class 324 : ELECTRICITY: MEASURING AND TESTING
 324/500 FAULT DETECTING IN ELECTRIC CIRCUITS AND OF
 ELECTRIC COMPONENTS
 324/537 .Of individual circuit component or element
 324/765 ..Test of semiconductor device

5 324/638 (1 OR, 4 XR)
 Class 324 : ELECTRICITY: MEASURING AND TESTING
 324/600 IMPEDANCE, ADMITTANCE OR OTHER QUANTITIES
 REPRESENTATIVE OF ELECTRICAL STIMULUS/RE

SPONSE

324/629 RELATIONSHIPS
 .Distributive type parameters
 324/637 ..Using transmitted or reflected microwaves
 324/638 ...Scattering type parameters (e.g., complex
 reflection coefficient)

5 365/230.05 (3 OR, 2 XR)
 Class 365 : STATIC INFORMATION STORAGE AND RETRIEVAL
 365/230.01 ADDRESSING
 365/230.05 .Multiple port access

4 324/158.1 (1 OR, 3 XR)
 Class 324 : ELECTRICITY: MEASURING AND TESTING
 324/158.1 MISCELLANEOUS

4 714/724 (1 OR, 3 XR)
 Class 714 : ERROR DETECTION/CORRECTION AND FAULT
 DETECTION/RECOVERY
 714/699 PULSE OR DATA ERROR HANDLING
 714/724 .Digital logic testing

4 714/727 (2 OR, 2 XR)
 Class 714 : ERROR DETECTION/CORRECTION AND FAULT

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DETECTION/RECOVERY

714/699 PULSE OR DATA ERROR HANDLING
714/724 .Digital logic testing
714/726 ..Scan path testing (e.g., level sensitive sca
n
design (LSSD))
714/727 ...Boundary scan

4 714/736 (3 OR, 1 XR)
Class 714 : ERROR DETECTION/CORRECTION AND FAULT
DETECTION/RECOVERY
714/699 PULSE OR DATA ERROR HANDLING
714/724 .Digital logic testing
714/736 ..Device response compared to expected
fault-free response

3 324/637 (1 OR, 2 XR)
Class 324 : ELECTRICITY: MEASURING AND TESTING
324/600 IMPEDANCE, ADMITTANCE OR OTHER QUANTITIES
REPRESENTATIVE OF ELECTRICAL STIMULUS/RES
ONSE
RELATIONSHIPS
324/629 .Distributive type parameters
324/637 ..Using transmitted or reflected microwaves

3 324/763 (0 OR, 3 XR)
Class 324 : ELECTRICITY: MEASURING AND TESTING
324/500 FAULT DETECTING IN ELECTRIC CIRCUITS AND OF
ELECTRIC COMPONENTS
324/537 .Of individual circuit component or element
324/763 ..DUT including test circuit

3 327/108 (3 OR, 0 XR)
Class 327 : MISCELLANEOUS ACTIVE ELECTRICAL NONLINEAR
DEVICES, CIRCUITS, AND SYSTEMS
327/100 SIGNAL CONVERTING, SHAPING, OR GENERATING
327/108 .Current driver

3 365/201 (1 OR, 2 XR)
Class 365 : STATIC INFORMATION STORAGE AND RETRIEVAL
365/189.01 READ/WRITE CIRCUIT
365/201 .Testing

3 702/85 (2 OR, 1 XR)
Class 702 : DATA PROCESSING: MEASURING, CALIBRATING, OR
TESTING
702/85 CALIBRATION OR CORRECTION SYSTEM

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2 324/627 (1 OR, 1 XR)
 Class 324 : ELECTRICITY: MEASURING AND TESTING
 324/600 IMPEDANCE, ADMITTANCE OR OTHER QUANTITIES
 REPRESENTATIVE OF ELECTRICAL STIMULUS/RES

PONSE

RELATIONSHIPS

324/612 .Parameter related to the reproduction or fidelity of a signal affected by a circuit under test

324/627 ..Shielding effectiveness (SE)

2 326/30 (0 OR, 2 XR)
 Class 326 : ELECTRONIC DIGITAL LOGIC CIRCUITRY
 326/21 SIGNAL SENSITIVITY OR TRANSMISSION INTEGRITY
 326/30 .Bus or line termination (e.g., clamping, impedance matching, etc.)

2 326/90 (0 OR, 2 XR)
 Class 326 : ELECTRONIC DIGITAL LOGIC CIRCUITRY
 326/62 INTERFACE (E.G., CURRENT DRIVE, LEVEL SHIFT, ETC.)
 326/82 .Current driving (e.g., fan in/out, off chip driving, etc.)
 326/89 ..Bipolar transistor
 326/90 ...Bus driving

2 327/563 (0 OR, 2 XR)
 Class 327 : MISCELLANEOUS ACTIVE ELECTRICAL NONLINEAR DEVICES, CIRCUITS, AND SYSTEMS
 327/524 SPECIFIC IDENTIFIABLE DEVICE, CIRCUIT, OR SYSTEM
 327/560 .Nonlinear amplifying circuit
 327/563 ..With differential amplifier

2 327/68 (0 OR, 2 XR)
 Class 327 : MISCELLANEOUS ACTIVE ELECTRICAL NONLINEAR DEVICES, CIRCUITS, AND SYSTEMS
 327/1 SPECIFIC SIGNAL DISCRIMINATING (E.G., COMPARING, SELECTING, ETC.) WITHOUT SUBS

EQUENT CONTROL

327/50 .By amplitude
 327/63 ..Comparison between plural varying inputs
 327/68 ...Input provides varying reference signal

2 356/364 (0 OR, 2 XR)
 Class 356 : OPTICS: MEASURING AND TESTING
 356/364 BY POLARIZED LIGHT EXAMINATION

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2 356/73.1 (1 OR, 1 XR)
Class 356 : OPTICS: MEASURING AND TESTING
356/73.1 FOR OPTICAL FIBER OR WAVEGUIDE INSPECTION

2 365/189.04 (1 OR, 1 XR)
Class 365 : STATIC INFORMATION STORAGE AND RETRIEVAL
365/189.01 READ/WRITE CIRCUIT
365/189.04 .Simultaneous operations (e.g., read/write)

2 365/200 (0 OR, 2 XR)
Class 365 : STATIC INFORMATION STORAGE AND RETRIEVAL
365/189.01 READ/WRITE CIRCUIT
365/200 .Bad bit

2 702/76 (1 OR, 1 XR)
Class 702 : DATA PROCESSING: MEASURING, CALIBRATING, OR
TESTING
702/1 MEASUREMENT SYSTEM IN A SPECIFIC ENVIRONMENT
702/57 .Electrical signal parameter measurement syste

m

702/66 ..Waveform analysis
702/75 ...Frequency
702/76Frequency spectrum

2 713/500 (0 OR, 2 XR)
Class 713 : ELECTRICAL COMPUTERS AND DIGITAL PROCESSING
SYSTEMS: SUPPORT
713/500 CLOCK, PULSE, OR TIMING SIGNAL GENERATION OR
ANALYSIS

2 714/726 (2 OR, 0 XR)
Class 714 : ERROR DETECTION/CORRECTION AND FAULT
DETECTION/RECOVERY
714/699 PULSE OR DATA ERROR HANDLING
714/724 .Digital logic testing
714/726 ..Scan path testing (e.g., level sensitive sca

n

design (LSSD))

2 714/740 (2 OR, 0 XR)
Class 714 : ERROR DETECTION/CORRECTION AND FAULT
DETECTION/RECOVERY
714/699 PULSE OR DATA ERROR HANDLING
714/724 .Digital logic testing
714/738 ..Including test pattern generator
714/740 ...Having analog signal

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6614237 90
6407542 85
6177804 76
4775977 73
6087843 69
5307284 67
6060888 67
6396285 67
6417674 67
6571187 67
5793213 66
5260947 63
5996102 62
5999008 61
6194911 61
5942922 59
6057716 59
5930735 59
6016566 59
6028438 59
6356096 59
6163223 59
5668819 59
5831440 59
6256760 59
6260166 59
6397354 59
6446230 59
6449033 59
6529844 59
6606158 59
5734613 57
5742557 57
5896330 57
6232815 57
5982827 56
5673275 56
5233564 55
4808913 54
5430400 54
6166569 54
6188227 54
6281699 54
6329833 54
6380533 54
6414496 54
6421624 54
6052810 54

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5818243 54
5561638 53